

Edge-TCT measurements of heavily irradiated HPK p-type sensors

Thursday 18 November 2010 10:20 (20 minutes)

HPK p-type sensor was irradiated in steps with reactor neutrons up to the fluence of $1e16 \text{ cm}^{-2}$. After each step several Edge-TCT measurements were performed during initial stage of annealing. Charge collection properties, drift velocity profiles were investigated as a function of annealing, fluence and bias voltage.

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Session Classification: Development and Characterization of Strip and Pixel Sensors